

Energy-Aware Computing

Lecture 6: Gate-level energy-saving techniques

Parameters

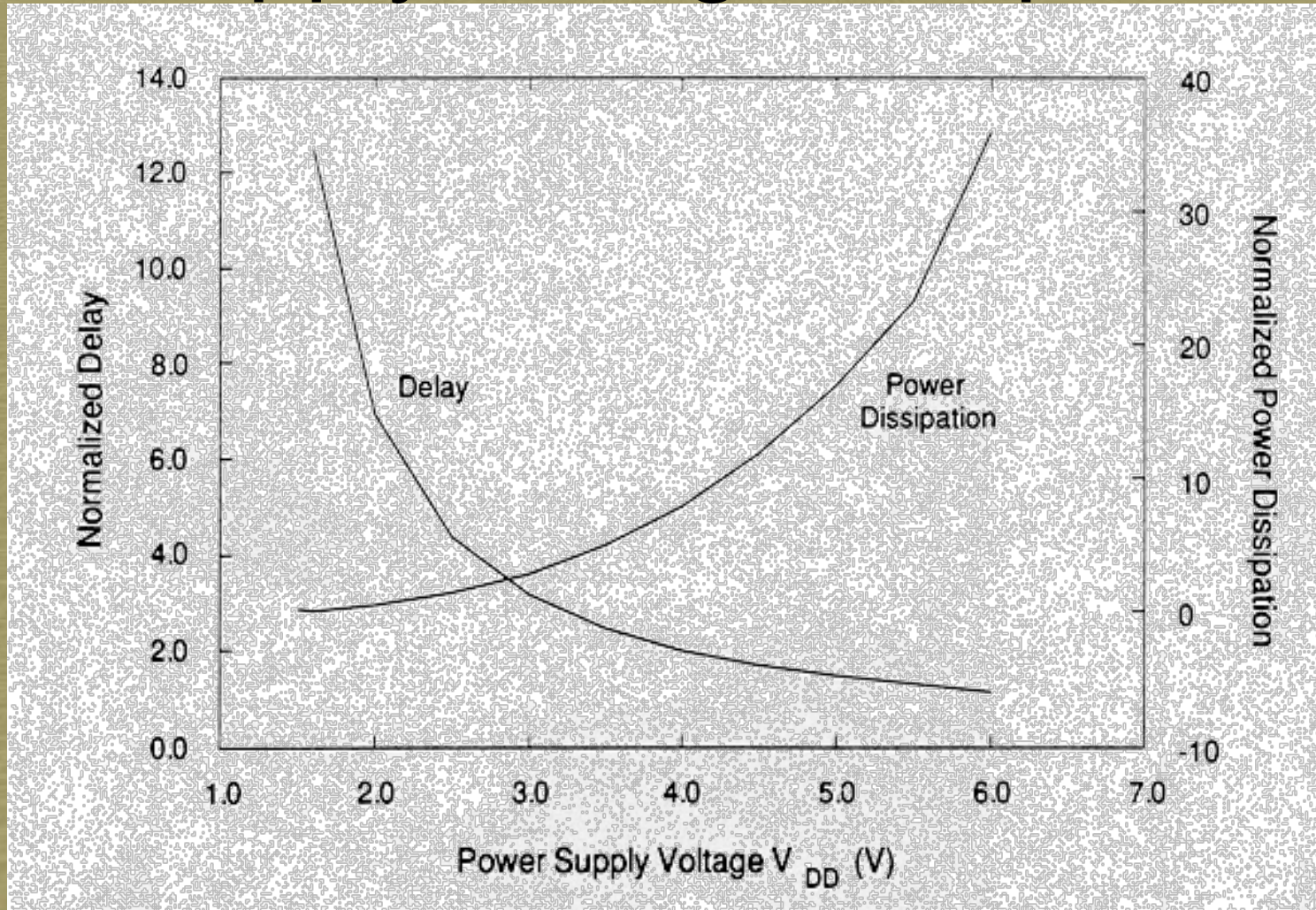
$$P = C_L \cdot V_{DD}^2 \cdot P_{0 \rightarrow 1} \cdot f$$

- Frequency - clock rate
 - Ok for power, no effect for energy
- Supply voltage
 - Quadratic effect (!) but slows down circuit
- Capacitance
- Activity
 - “algorithm”/design
 - Other issues, e.g. glitches

Voltage

- Relation between voltage and speed
 - Threshold voltage
 - How low can we go?
- Dual supply voltage
- Low voltage signal swing
- Architecture driven voltage reduction
- Dynamic voltage scaling

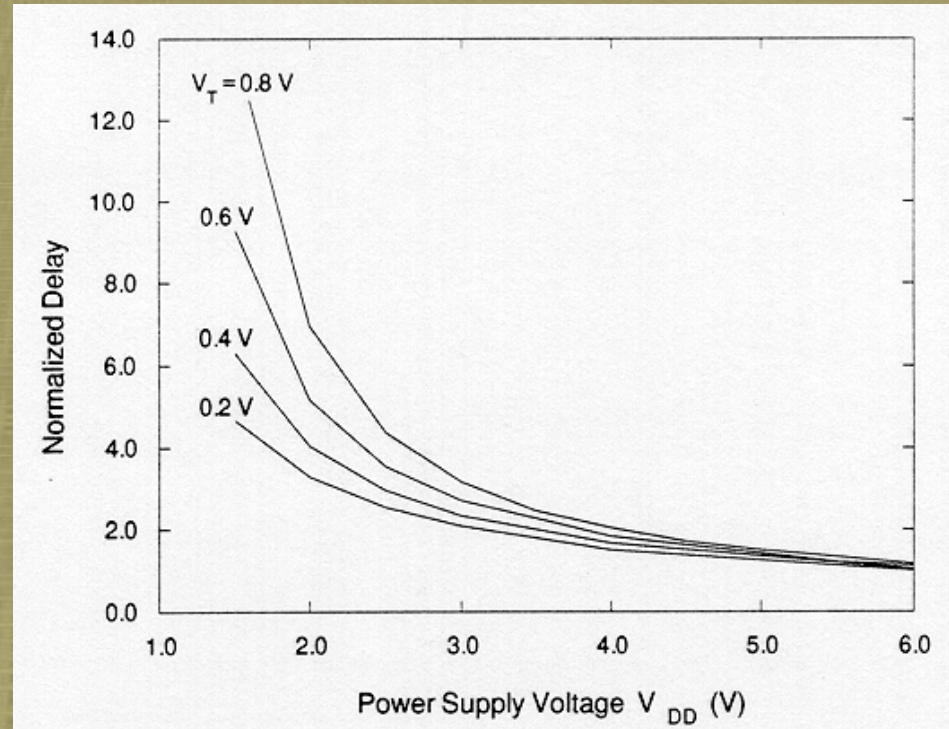
Supply voltage vs speed



Source: Mlynek, Leblebici, design of VLSI systems course, EPFL

Effect of threshold voltage

$$T_d \propto \frac{V_{dd}}{(V_{dd} - V_t)^2}$$



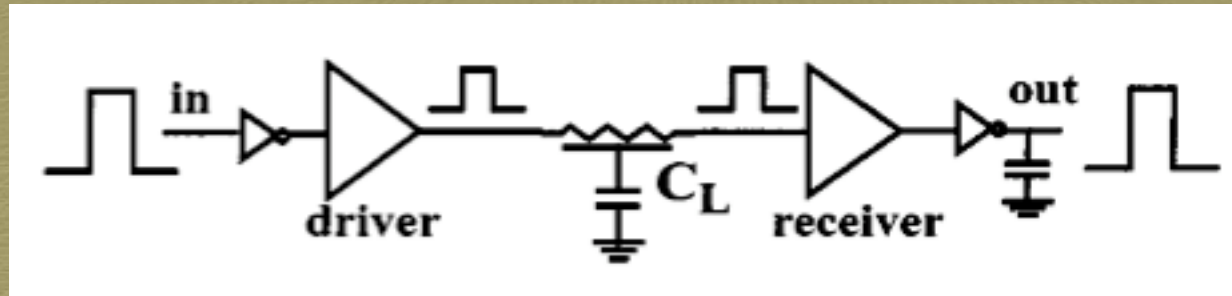
Source: Mlynek, Leblebici, design of VLSI systems course, EPFL

- Why not scale V_t (and V_{dd}) aggressively?
 - Leakage increases exponentially with V_t
 - More on leakage in a future lecture

Dual-supply voltages

- Two (or more) supply voltages
 - High V_{dd} for gates on the critical path
 - Low V_{dd} for gates off the path
- Little if any speed loss
- Expensive
 - More design effort. E.g. level converters
 - More space: 2 power delivery systems
- Not popular

Low voltage swing



- Reduce the voltage swing of key signals
 - Signal recovery required at receiver
 - Differential signaling (2 wires per bit)
 - Single-rail with local reference voltage at receiver
- Can be combined with multi-value logic

Low voltage swing

$$P = C_{eff} \cdot V_{dd} \cdot V_{swing} \cdot f$$

- Good targets
 - High capacitance wires, e.g. busses, the clock
 - High activity wires, e.g. the clock
- Reduced immunity to noise
 - Signal may be lost
 - Noise is becoming a hard problem in deep sub-micron technologies

Architecture-driven voltage scaling

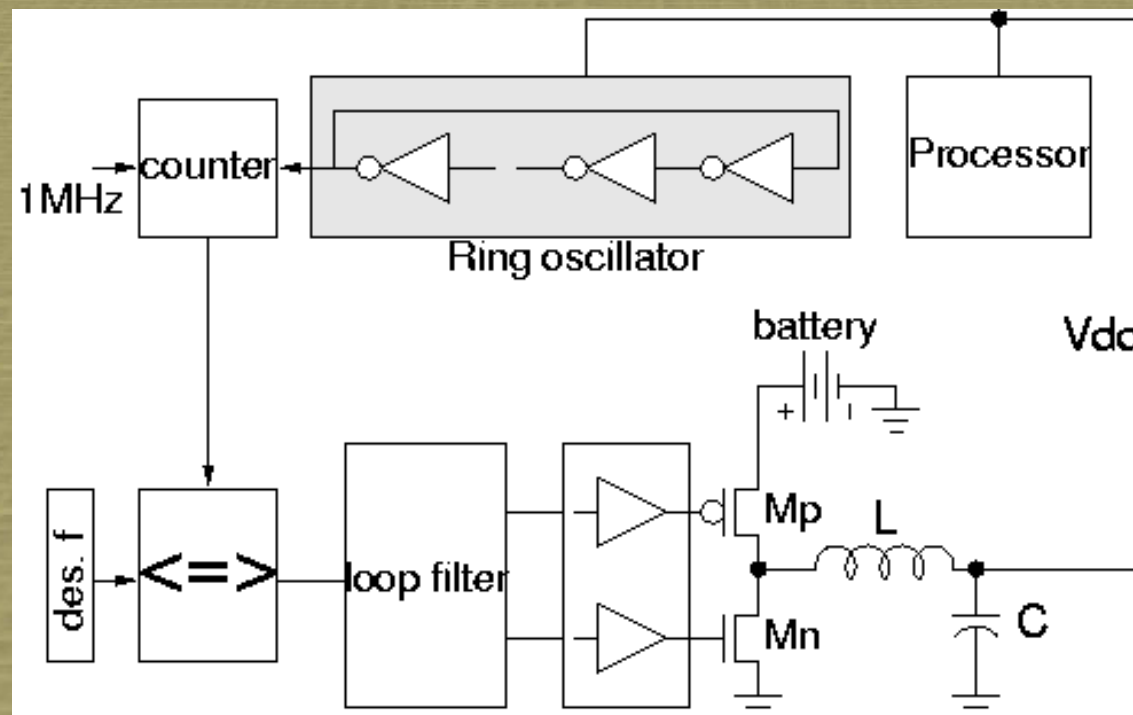
- Aggressively reduce the supply voltage
- Recover lost speed by parallelism
 - Extra pipeline stages and/or unit duplication
 - Mostly good for maintaining *throughput* rate
 - Operations start at a fast rate
 - *Latency* can still suffer
 - Results take longer to appear
 - Area increase, sometimes dramatic
- Adder-comparator example from Chandrakassan'95 (duplication)
 - $C_{\text{par}} = 2.15C_{\text{ref}}, V_{\text{par}} = 0.58V_{\text{ref}}, f_{\text{par}} = f_{\text{ref}}/2$
 - $P_{\text{par}} = 0.36P_{\text{ref}}$

Dynamic voltage scaling

- Allow run-time, dynamic adaptation of supply voltage and operating frequency
 - Multiple power/speed operation points
 - Software (OS) decides which is best
- Careful circuit design required
 - Some circuit types can fail
- Extra circuit, voltage regulator, required
 - Some energy loss incurred

Voltage regulator

- “User” sets required frequency (des. f), regulator finds corresponding voltage
- Ring oscillator matches critical path in all conditions



Src: Burd, Brodersen. Design Issues for Dynamic Voltage Scaling. ISLPED'00

Switched capacitance

- Logic style
 - Static vs dynamic logic gates
 - Transistor sizes
- Logic function
- Circuit topology
- Data statistics
- Sequencing of operations
 - E.g. encoding of FSM states

Static vs dynamic

- Dynamic circuits remove the PMOS stack with 1 transistor controlled by a “clock” signal
 - Precharge in every cycle
 - Discharge depending on input values
- Dynamic circuits have
 - Higher switching activities
 - Higher clock load
 - ✓ No spurious transitions (glitches)
 - ✓ Lower input capacitances
- No clear winner in general
- Dynamic circuits are hard to use in automated design flow

Low energy logic gates

- Transistor sizing
 - Small transistors in logic gates out of critical path
 - Lower input capacitances, smaller circuits, lower interconnect capacitances
- Dual threshold voltages
 - Enables the use of low supply voltage
 - Use low- V_t (fast) gates for critical path
 - Use high- V_t (slow) gates for other paths

Logic function

- The probability of a $0 \rightarrow 1$ transition at the output depends on the logic function
- E.g. 2-input NOR with all possible input combinations equally likely. $p(0) = 3/4$, $p(1) = 1/4$
 - $P_{0 \rightarrow 1} = p(0)p(1) = 3/16$
- 2-input XOR
 - $P_{0 \rightarrow 1} = 1/2 \cdot 1/2 = 1/4$
- Extended to networks of logic gates

Signal probabilities

- Signal probability:
 - Average fraction of clock cycles when signal is high
- Propagate from inputs using Shannon's decomposition:

$$y = f(x_0, \dots, x_n) = x_i f_{x_i} + \bar{x}_i f_{\bar{x}_i}$$

$$f_{x_i} = f(x_0, \dots, 1, \dots, x_n)$$

$$f_{\bar{x}_i} = f(x_0, \dots, 0, \dots, x_n)$$

$$\begin{aligned} P(y) &= P(x_i f_{x_i}) + P(\bar{x}_i f_{\bar{x}_i}) \\ &= P(x_i)P(f_{x_i}) + P(\bar{x}_i)P(f_{\bar{x}_i}) \end{aligned}$$

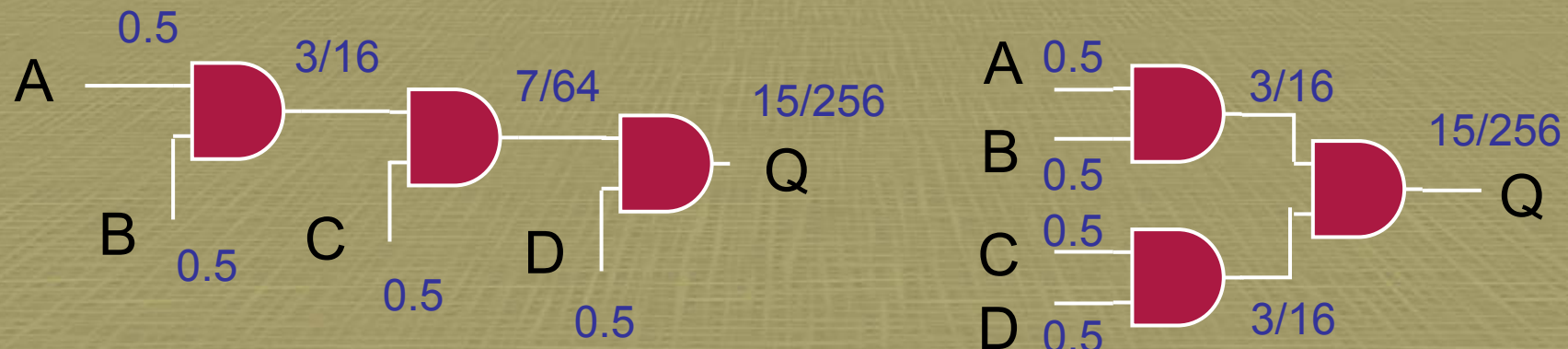
Transition density

- For power/energy we need to find the probability of transition from 0 to 1
- **Transition density** $D(y)$ - average number of transitions per unit time
 - Includes both 0-1 and 1-0 transitions
 - $D(y) = 2 \cdot P_{0 \rightarrow 1}(y) \cdot f$
- For a transition on x to cause a transition on y
 $\partial y / \partial x_i = f_{x_i} \oplus f_{\bar{x}_i} = 1$
- Total density of y : $D(y) = \sum P(\partial y / \partial x_i) D(x_i)$
- Average power: $P = \sum 0.5 C_y V_{dd}^2 D(y)$

Circuit topology

- Two components of switching activity
 - Static - only up to 1 toggle per gate
 - Timing behaviour is ignored
 - Dynamic
 - Spurious transitions, glitches
- Balancing the delay paths reduces glitching

Circuit topology example



- Chain topology has lower combined static switching activity
- Tree topology is better for reducing glitches
- Similarly it is better to move signals with high transition rate as close to the output as possible

Glitches

- Estimated to account for 15-20% of dynamic power
- Not present in dynamic logic circuits
- Glitches depend on the *logic depth* of the circuit
 - Max number of logic gates from input to output
 - Arrival times spread due to delay imbalances
- Pipelining reduces logic depth, reduces power due to glitches
 - But more *clock load* - capacitance driven by the clock signal in every cycle

Summary

- Voltage reduction
 - Relationship with speed
 - Dual supply, dual V_t
 - Low swing, architecture-driven scaling, dynamic scaling
- Effective capacitance
 - Logic style
 - Logic function
 - Probabilistic estimation of power
 - Glitches